3GPP TSG-T (Terminals) Meeting #10
Bangkok, Thailand, 6 - 8 December, 2000

Tdoc TP-000249

Agenda item:

Source: **Nokia**

Title: **Ungency to resolve test tolerance issue in TS34.121**

Document for: **Discussion and Decision**

Introduction

In 3GPP TSG T1/RF SWG it has been agreed to relax the core specification values with the test tolerance and to implement the relaxed value into the test specifications. This is the result of a long discussions, including the creation of a new recommendation ITUR-R [IMT.UNCERTAIN]. The recommendation concludes that from a technical perspective, applying "Never fail a good DUT" to a test limit that equals the core specification value leads to the same result as applying "Shared risk" to a test limit being a relaxation of the core specification value.

Applied to the UE FDD test specifications, this means that the core specification values are left untouched while test limits in TS 34 .121 may be relaxed with the test tolerance. At this point there is agreement on this principle, but it has not been implemented in the test specifications yet.

Urgency of resolving the test tolerance in TS 34.121

The FDD UE test specification TS 34.121 is the basis for the Japanese TELEC test specifications, with the value also written into Japanese law. The draft Harmonised Standard for UTRA FDD UE (in support of the R&TTE directive) is also based on TS 34.121.

RAN WG4 decided to implement relaxation of test limits to FDD BS test specification TS25.141 in December/2000 due to ungency of Japanese and European regulatory requirements. In T1/RF meeting#16 (13^{th} - 15^{th} November, 2000) similar approach was also discussed, but it was considered impossible to complete test tolerance issue by December/2000. However the urgency of proceeding in this matter exists, and in this document it is proposed the way forward.

Test case list based on Japan Radio Law requirements and Essential requirements of article 3.2 of the R&TTE Directive

The following test case list is based on Japan Radio Law requirements and Essential requirements of Article 3.2 of the R&TTE Directive. In last TSG RAN WG4 meeting some of the items was proposed to be without any relaxation of test limit, these are noted in brackets :

- Transmitter maximum output power
- Frequency error
- Transmitter spectrum emission mask
- Occupied Band Width
- Transmitter spurious emissions (test tolerance is decided to be zero)
- Transmitter minimum output power
- Adjacent Channel Leakage Power Ratio (ACLR)
- Receiver adjacent channel selectivity (ACS)
- Receiver blocking characteristics
- Receiver spurious response
- Receiver spurious emissions (test tolerance is decided to be zero)
- Out-of-synchronisation handling of output power

Proposed way forward

A way to forward is proposed to conclude this issue as soon as possible.

1. T1/RF will agree on which test tolerance that should be zero or not, based on the test case list above in this document. It is suggested that the basis of decision should be same as in TSG RAN WG4 for UTRA BTS for the sake of consistency of procedures. Also the handling of each reuirement in regulatory bodies will be simplier if UE and BTS has same procedure of uncertainty handling.
2. A CR will be drafted for the clauses in TS 34.121 that correspond to non-zero test tolerances. The CRs should be distributed on T1/RF e-mail reflector during December/2000 and January/2001 for review to get straightforward and well prepared approval for them in next T1/RF meeting#17, on 5th – 7th February, 2001.

Discussion and decision

The delegates in TSG T meeting#10 is requested to discuss and conclude the way forward on this issue. Since urgency to resolve test tolerance issue is obvious, TSG T meeting is asked to encourage TSG T1/RF and T1 to complete this issue at the latest in T1/RF meeting#17 on 5th - 7th February, 2001 and T1 plenary meeting#10 on 8th - 9th, February, 2001. This will ensure a smooth handling of rel-99 test requirements in other working groups waiting these decisions.